

**REMARKS**

Applicants wish to thank Examiner Dote for indicating allowability of Claim 13-14 if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Applicants respectfully request reconsideration of the application, as amended, in view of the following remarks.

Applicants note that Claim 4 was not rejected over Yagi et al, Claims 2 and 4 were not rejected over Nanya et al, Claims 2, 4 and 6 were not rejected over Nakanishi et al combined with Hitake and Shirai, Claim 6 was not rejected over Nakanishi et al combined with Anno. Since the limitations of Claims 2, 4 and 6 have been included in Claims 1 and 24, the present Claims should therefore be allowable.

The rejection of Claims 1-23, 25 and 27 under 35 U.S.C. § 112, second paragraph, is obviated by the amendments of the claims.

The objection to the specification is obviated by the amendments to the specification and by the amendment of Claim 27.

Furthermore, all inventors designated in this application were under obligation to assign the results of their research to Ricoh Company, Ltd. at the time the invention was made.

Applicants note that they responded to the objections regarding various Information Disclosure Statements on May 31, 2005.

Applicants note that MPEP §821.04 states, "if applicant elects claims directed to the product, and a product claim is subsequently found allowable, withdrawn process claims which depend from or otherwise include all the limitations of the allowable product claim will be rejoined." Applicants respectfully submit that should the elected group be found allowable, the non-elected claims 26 and 28 should be rejoined.

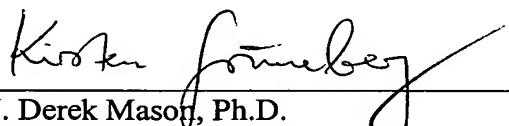
Applicants respectfully request that the Examiner acknowledge that the references AA and AB cited in the **Information Disclosure Statement**, filed in the above-identified application on **September 26, 2003**, have been considered. For the Examiner's convenience a copy of Form PTO 1449 as filed on **September 26, 2003**, is attached herewith.

Applicants respectfully request that the Examiner acknowledge that the references cited in the **Information Disclosure Statement**, filed in the above-identified application on **May 31, 2005**, have been considered. For the Examiner's convenience a copy of Form PTO 1449 as filed on **May 31, 2005**, is attached herewith.

This application presents allowable subject matter, and the Examiner is kindly requested to pass it to issue. Should the Examiner have any questions regarding the claims or otherwise wish to discuss this case, he is kindly invited to contact Applicants' below-signed representative, who would be happy to provide any assistance deemed necessary in speeding this application to allowance.

Respectfully submitted,

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242938US0		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yohichiroh WATANABE, et al.			
				FILING DATE HEREWITH		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA		6,503,676	01/07/03	YAMASHITA, ET AL.			
AB		6,593,048	07/15/03	SASAKI, ET AL.			
AC							
AD							
AE							
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
AO		03-242402	08/29/91	JAPAN w/ Abstract	YES		NO
AP		03-360181	12/30/91	JAPAN w/ Abstract			
AQ		05-130665	06/01/93	JAPAN w/ Abstract			
AR		07-055947	03/15/95	JAPAN w/ Abstract			
AS		07-053371	02/16/95	JAPAN w/ Abstract			
AT		08-064321	03/21/96	JAPAN w/ Abstract			
AU		09-333611	11/17/97	JAPAN w/ Abstract			
AV		11-362390	12/21/99	JAPAN w/ Abstract			
AW		61-278069	11/20/86	JAPAN w/ Abstract			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AX						
	AY						
	AZ						
						<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				Date Considered			

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\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242938US0	SERIAL NO. 10/670,320	
<p style="text-align: center;"><b>O I P E</b> LIST OF REFERENCES CITED BY APPLICANT AUG 31 2005 U.S. PATENT &amp; TRADEMARK OFFICE</p>				APPLICANT Yohichiroh WATANABE, et al.		
				FILING DATE September 26, 2003	GROUP 1756	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	AA	2005/0026064 A1	02-03-05	Sugiura et al		
	AB	2004/0234882 A1	1125-04	Matsui et al		
	AC	2005/0003288 A1	01-06-05	Sugiyama et al		
	AD	2004/0265721 A1	12-30-04	Matsuoka et al		
	AE	2004/0259013 A1	12-23-04	Ohtani et al		
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<b>FOREIGN PATENT DOCUMENTS</b>						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO	05-061242	03-12-093	Japan (w/English Abstract)		x
	AP	05-181301	07-23-93	Japan (w/English Abstract)		X
	AQ	06-342224	12-13-94	Japan (w/English Abstract)		X
	AR	08-254853	10-01-96	Japan (w/English Abstract)		X
	AS	08-220808	08-30-96	Japan (w/English Abstract)		X
	AT	09-258480	10-03-97	Japan (w/English Abstract)		X
	AU	11-149180	06-02-99	Japan (w/English Abstract)		X
	AV	2001-175025	06-29-01	Japan (w/English Abstract)		x
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>						
	AW	Patent Abstracts of Japan, English Abstract of JP 05-061242				
	AX	Patent Abstracts of Japan, English Abstract of JP 05-181301				
	AY	Patent Abstracts of Japan, English Abstract of JP 06-342224				
	AZ	Patent Abstracts of Japan, English Abstract of JP 08-254853			<input type="checkbox"/> Additional References sheet(s) attached	
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
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	AP						
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	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
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AY	Patent Abstracts of Japan, English Abstract of JP 11-149180						
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